

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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	N	WO 00/27379	05-2000	WO	Yayon et al.	---
	O					
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NON-PATENT DOCUMENTS

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